

ISSUED BY Shenzhen BALUN Technology Co., Ltd.



FOR

Smart Phone

ISSUED TO Infinity System S.L.

Crtra A-2, Km 48.5, Pol. Ind. De Cabanillas, Parcela 12B, 19171, Guadalajara, Spain.





Report No.: BL-SZ1490064-401

EUT Type: Smart Phone

Model Name: TM5QWM

Brand Name: AIRIS

Test Standard: 47 CFR Part 15 Subpart B

FCC ID:

2AC99-TM5QWM

Test conclusion: PASS

Test Date: Sep 4, 2014 ~ Sep 19, 2014

Date of Issue:

Sep 24, 2014

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Revision History

VersionIssue DateRevisionsRev. 01Sep 24,2014Initial Issue

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1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,	
Audiess	Nanshan District, Shenzhen, Guangdong Province, P. R. China	
Phone Number	+86 755 6683 3402	
Fax Number	+86 755 6182 4271	

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.		
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,		
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China		
	The laboratory has been listed by Industry Canada to perform		
	electromagnetic emission measurements. The recognition numbers of		
	test site are 11524A-1.		
	The laboratory has been listed by US Federal Communications		
	Commission to perform electromagnetic emission measurements. The		
	recognition numbers of test site are 832625.		
Accreditation Certificate	The laboratory has met the requirements of the IAS Accreditation Criteria		
	for Testing Laboratories (AC89), has demonstrated compliance with		
	ISO/IEC Standard 17025:2005. The accreditation certificate number is		
	TL-588.		
	The laboratory is a testing organization accredited by China National		
	Accreditation Service for Conformity Assessment (CNAS) according to		
	ISO/IEC 17025. The accreditation certificate number is L6791.		
	All measurement facilities used to collect the measurement data are		
Description	located at Block B, FL 1, Baisha Science and Technology Park, Shahe Xi		
Description	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China		
	518055		

1.3 Test Environment Condition

Ambient Temperature	15 to 35°C
Ambient Relative Humidity	30 to 60%
Ambient Pressure	86 to 106 kPa



1.4 Announce

- (1) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (2) The test report is invalid if there is any evidence and/or falsification.
- (3) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (4) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



2 PRODUCT INFORMATION

2.1 Applicant

Applicant	Infinity System S.L.		
Address	Crtra A-2, Km 48.5, Pol. Ind. De Cabanillas, Parcela 12B, 19171,		
	Guadalajara, Spain.		

2.2 Manufacturer

Manufacturer REVO TECHNOLOGY (HK) LIMITED	
A dalana a a	Room 1318-19, Hollywood Plaza, 610 Nathan Road, Mongkok, Kowloon,
Address	HK

2.3 General Description for Equipment under Test (EUT)

EUT Type	Smart Phone	
Model Name	TM5QWM	
Series Model Name	N/A	
Hardware Version	HCT-K56MB-A2	
Software Version	N/A	
Network and Wireless connectivity	GSM, WCDMA	
About the Product	The equipment is Smart Phone, intended for used with information technology equipment.	



2.4 Ancillary Equipment

	Battery		
	Brand Name	AIRIS	
	Model No	T5QWMCH	
Ancillary Equipment 1	Serial No	(N/A. marked #1 by test site)	
Ancillary Equipment 1	Capacitance	2000mAh	
	Rated Voltage	3.7V	
	Charge Limit	4.2V	
	Extreme Voltage	Low: 3.5V / High:4.2V	
Annillant Equipment 2	AC Adapter		
	Brand Name	AIRIS	
	Model No	T5QWMCH	
Ancillary Equipment 2	Serial No	(N/A. marked #1 by test site)	
	Rated Input	~ 220V, 200mA, 60Hz, 5W	
	Rated Output	= 5V, 1000mA, 5W, 60Hz	
Ancillary Equipment 3	Earphone		
Ancillary Equipment 4	USB Cable		



3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title	
1	FCC 47 CFR Part 15 Subpart	Unintentional Radiators	
l	B (10-1-09 Edition)		
	ANSI C63.4-2009	American National Standard for Standard for Methods of	
		Measurement of Radio-Noise Emissions from Low-Voltage	
2		Electrical and Electronic Equipment in the Range of 9 kHz to	
		40 GHz	

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	PASS	Annex A .1
2	Conducted Emission, AC Ports	15.107	PASS	Annex A .2

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9KHz-30MHz)	1.12 dB
Radiated emissions (30MHz-1GHz)	2.11 dB
Radiated emissions (1GHz-18GHz)	3.31 dB



4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments

Environment Parameter	Selected Values During Tests						
Environment Parameter	Temperature	Voltage	Relative Humidity				
Normal Temperature,	2222						
Normal Voltage (NTNV)	23°C~25°C	AC 110V/60Hz	50%-55%				

4.2 Test Equipment List

	R	adiated Em	ission Test			
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2014.07.07	2015.07.06	\boxtimes
Test Antenna- Loop(9kHz- 30MHz)	SCHWARZBECK	FMZB 1519	1519-037	2013.07.02	2015.07.01	\boxtimes
Test Antenna- Bi-Log(30MHz -3GHz)	SCHWARZBECK	VULB 9163	9163-624	2013.07.03	2015.07.02	\boxtimes
Test Antenna- Horn(1- 18GHz)	SCHWARZBECK	BBHA 9120D	9120D-1148	2013.07.02	2015.07.01	\boxtimes
Test Antenna- Horn(15- 26.5GHz)	SCHWARZBECK	BBHA 9170	9170-305	2013.07.02	2015.07.01	
Anechoic Chamber	RAINFORD	9m*6m*6 m	N/A	2013.10.07	2014.10.06	\boxtimes

	Co	onducted dis	turbance Test			
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2014.07.07	2015.07.06	\boxtimes
LISN	SCHWARZBECK	NSLK 8127	8127-687	2014.07.07	2015.07.06	\boxtimes
AMN	SCHWARZBECK	NNBM812 4	8124-509	2014.07.07	2015.07.06	
AMN	SCHWARZBECK	NNBM812 4	8124-510	2014.07.07	2015.07.06	
ISN	TESEQ	ISN T800	34449	2014.07.07	2015.07.06	



4.3 Test Enclosure list

Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	N/A	N/A	N/A	N/A	Special Handled	
Printer	HP	DESKJET 1000	N/A	N/A	N/A	
Keyboard	Logitech	Y-BP62a	N/A	N/A	N/A	
Mouse	Logitech	M100	N/A	N/A	N/A	
USB disk	Kingston	N/A	N/A	N/A	N/A	
TF Card	Kingston	N/A	N/A	N/A	N/A	
VGA Cable	N/A	N/A	N/A	1.5m	Shielded with core	
HDMI Cable	N/A	N/A	N/A	1.5m	Shielded with core	
DVI Cable	N/A	N/A	N/A	1.5m	Shielded with core	
Coaxial video cable	N/A	N/A	N/A	2m	Shielded with core	
Phone	BBK	HCD007TSD	N/A	N/A	N/A	
laptop	LENOVO	K29	N/A	N/A	N/A	\boxtimes

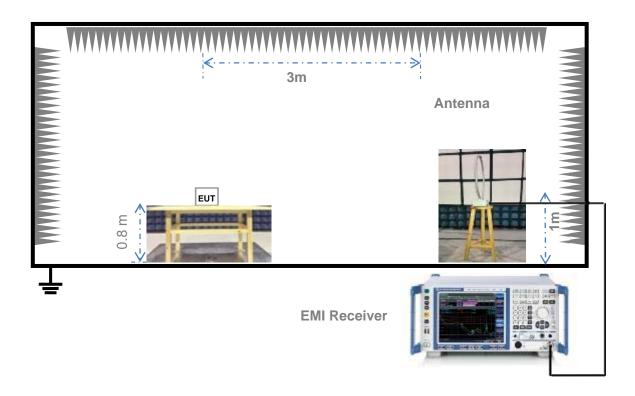
4.4 Test Configurations

Test Configurations (TC) No.	Description
	The USB Test mode
	The EUT configuration of the emission tests is EUT + USB cable + laptop +
TC01	earphone.
	During the measurement, the EUT is connected with a laptop via a USB cable
	supplied by applicant, the data is transmitting between the laptop and the EUT.
	The Camera Test mode
TC02	The EUT configuration of the emission tests is EUT + AC Charger + earphone.
	During the measurement, the EUT is working by the way of Camera.



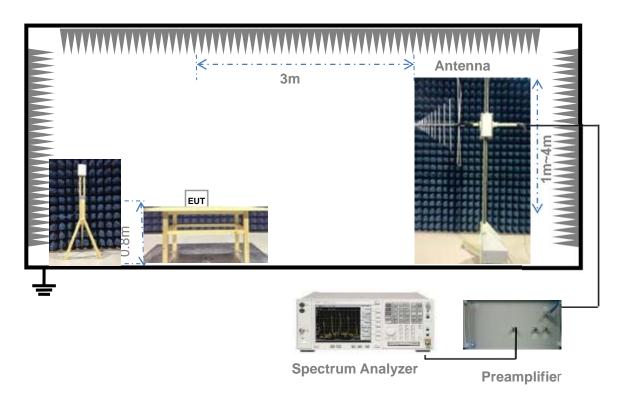
4.5 Test Setups

Test Setup 1



For Radiated Emission Test (Below 30MHz))

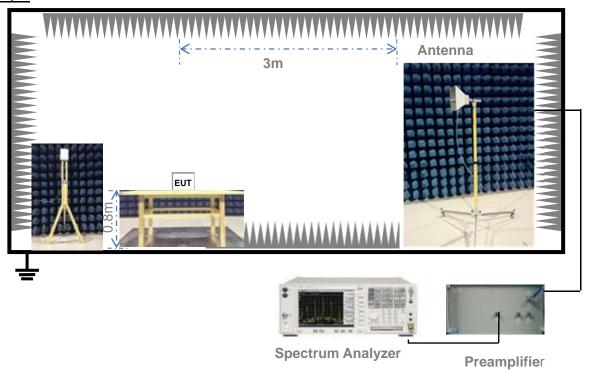
Test Setup 2



(For Radiated Emission Test (30MHz-1GHz))

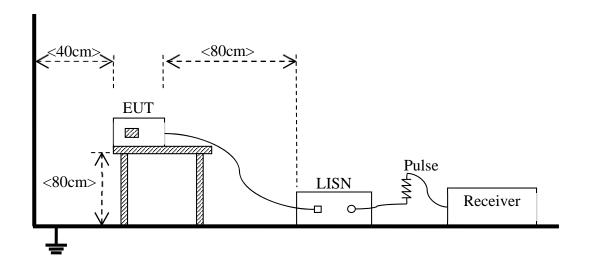


Test Setup 3



(For Radiated Emission Test (above 1GHz))

Test Setup 4



(For Conducted Emission, AC Ports Test)



4.6 Test Conditions

Test Case		Test Conditions	
	Test Env.	NTNV	
Radiated Emission	Test Setup	Test Setup 1&3	
	Test Configuration	TC01~TC02 Note	
Conducted Emission AC	Test Env.	NTNV	
Conducted Emission, AC	Test Setup	Test Setup 4	
Ports	Test Configuration	TC01~TC02 ^{Note}	

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report.



5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency (MHz)	Field Strength (μV/m)	Measurement Distance (m)
0.009 - 0.490	2400/F(kHz)	300
0.490 - 1.705	24000/F(kHz)	30
1.705 - 30.0	30	30
30 - 88	100	3
88 - 216	150	3
216 - 960	200	3
Above 960	500	3

NOTE:

- 1) Field Strength ($dB\mu V/m$) = 20*log [Field Strength ($\mu V/m$)].
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For above 1000MHz, limit field strength of harmonics: 54dBuV/m@3m (AV) and 74dBuV/m@3m (PK)

5.1.1.2 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.



5.1.2 Conducted Emission

5.1.2.1 Test Limit

Fraguency range (MHz)	Conducted Limit (dBμV)					
Frequency range (MHz)	Quasi-peak	Average				
0.15 - 0.50	66 to 56	56 to 46				
0.50 - 5	56	46				
5 - 30	60	50				

NOTE:

- 1) The limit is applicable to Class B ITE.
- 2) The lower limit shall apply at the band edges.
- 3) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

5.1.2.2 Test Procedure

The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.



ANNEX A TEST RESULTS

A.1 Radiated Emission

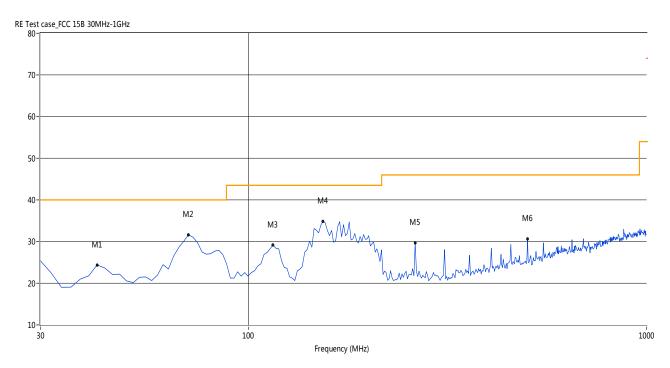
Note 1: The symbol of "--" in the table which means not application.

Note 2: For the test data above 1GHz, According the ANSI C63.4-2009, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Test Data and Plots

The low frequency, which started from 9 kHz to 30MHz, was pre-scanned and the result which was 20dB lower than the limit line per 15.31(o) was not reported.

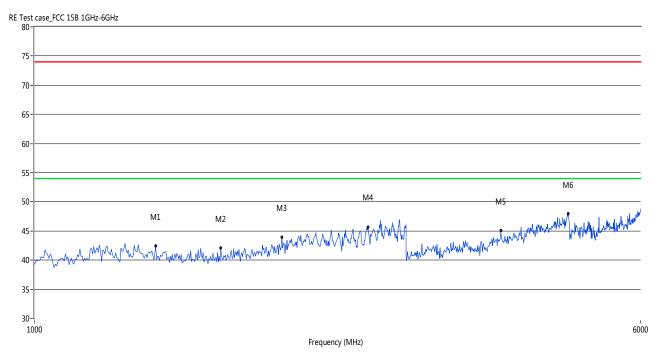
A.1.1 Test Antenna Vertical, 30MHz – 1GHz



Frequency	Peak	Q-peak	Average	Factor	PK Limit	QP Limit	AV Limit	Margin	Table (o)	Height	ANT	Verdict
(MHz)	(dBuV/m)	(dBuV/m)	(dBuV/m)	(dB)	(dBuV/m)	(dBuV/m)	(dBuV/m)	(dB)		(cm)		
41.62		24.39		-18.53		40.0		15.61	55.20	100	Vertical	PASS
70.66		31.63		-22.30		40.0		8.37	316.10	100	Vertical	PASS
115.19		29.16		-20.48		43.5		14.34	32.50	100	Vertical	PASS
153.91		34.89		-22.79		43.5		8.61	69.30	100	Vertical	PASS
262.34		29.73		-18.09		46.0		16.27	18.50	100	Vertical	PASS
502.42		30.63		-12.37		46.0		15.37	50.70	100	Vertical	PASS



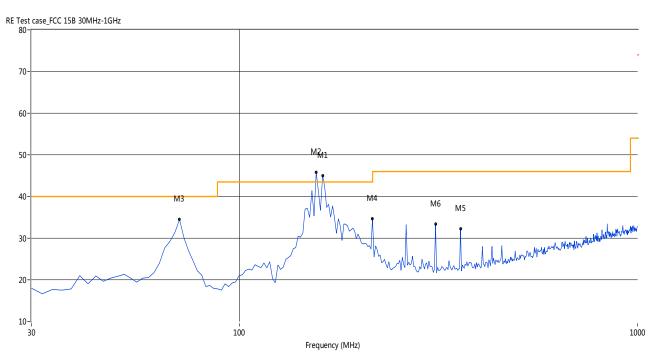
A.1.2 Test Antenna Vertical, 1GHz – 6GHz



Frequency Peak Q-peak Average Factor PK Limit QP Limit AV Limit Margin Table (o) Height ANT Verdict (dBuV/m) (MHz) (dBuV/m)(dBuV/m) (dBuV/m) (dB) (dBuV/m) (dBuV/m) (dB) (cm) 54.0 PASS 1431.14 42.44 -4.01 74.0 11.56 146.20 100 Vertical 1734.53 42.04 -4.10 74.0 --54.0 11.96 45.20 PASS --100 Vertical 2077.84 43.91 -2.14 74.0 54.0 10.09 304.20 100 Vertical PASS 2680.64 0.85 74.0 54.0 8.35 PASS 45.65 118.40 100 Vertical 74.0 54.0 8.96 3970.06 45.04 10.01 --139.00 100 Vertical PASS --4844.31 47.97 12.98 74.0 54.0 6.03 107.90 100 Vertical PASS



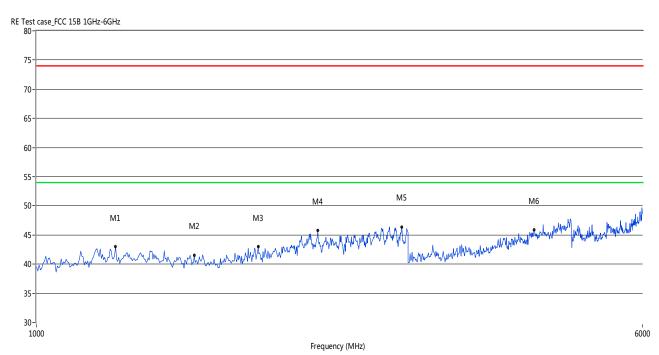
A.1.3 Test Antenna Horizontal, 30MHz – 1GHz



Frequency	Peak	Q-peak	Average	Factor	PK Limit	QP Limit	AV Limit	Margin	Table (o)	Height	ANT	Verdict
(MHz)	(dBuV/m)	(dBuV/m)	(dBuV/m)	(dB)	(dBuV/m)	(dBuV/m)	(dBuV/m)	(dB)		(cm)		
161.66		39.96		-22.37		43.5		3.54	65.00	187.90	Horizontal	PASS
155.85		40.91		-22.69		43.5		2.59	65.00	180.50	Horizontal	PASS
70.66		34.45		-22.30		40.0		5.55	22.80	100	Horizontal	PASS
215.87		34.68		-19.67		43.5		8.82	345.60	100	Horizontal	PASS
359.14		32.25		-15.48		46.0		13.75	357.10	100	Horizontal	PASS
310.74		33.41		-16.99		46.0		12.59	13.10	100	Horizontal	PASS



A.1.4 Test Antenna Horizontal, 1GHz – 6GHz



Frequency Peak Q-peak Average Factor PK Limit QP Limit AV Limit Margin Table (o) Height ANT Verdict (dBuV/m) (MHz) (dBuV/m)(dBuV/m) (dBuV/m) (dB) (dBuV/m) (dBuV/m) (dB) (cm) 54.0 1263.47 PASS 43.01 -4.04 74.0 10.99 162.10 100 Horizontal 1594.81 41.47 74.0 --54.0 12.53 122.70 PASS ---4.29 100 Horizontal 1926.15 43.05 -2.91 74.0 54.0 10.95 212.20 100 Horizontal PASS 2297.41 74.0 54.0 8.25 PASS 45.75 -0.48 111.60 100 Horizontal 2.03 74.0 54.0 7.61 PASS 2944.11 46.39 --122.70 100 Horizontal --4353.29 45.84 10.99 74.0 54.0 8.16 -0.00 100 Horizontal PASS



A.2 Conducted Emission

Test Data and Plots

A.2.1 L Phase



Frequency	Peak (dBm)	Q-peak	Average	Factor (dB)	QP Limit	AV Limit	Margin (dB)	Line	Verdict
(MHz)		(dBuV)	(dBuV)		(dBuV)	(dBuV)			
0.17	60.0		43.7	10.00	65.5	55.5	11.80	L Line	PASS
0.22	52.9		36.5	10.00	63.9	53.9	17.40	L Line	PASS
0.46	39.1	-	22.7	10.00	57.0	47.0	24.30	L Line	PASS
1.43	37.7	1	23.3	10.00	56.0	46.0	22.70	L Line	PASS
4.30	44.7	-	29.0	10.00	56.0	46.0	17.00	L Line	PASS
18.18	47.2	-	37.4	10.00	60.0	50.0	12.60	L Line	PASS



A.2.2 N Phase



Frequency	Peak (dBm)	Q-peak	Average	Factor (dB)	QP Limit	AV Limit	Margin (dB)	Line	Verdict
(MHz)		(dBuV)	(dBuV)		(dBuV)	(dBuV)			
0.22	54.7		39.7	10.00	63.9	53.9	14.20	N Line	PASS
0.39	41.4		25.6	10.00	59.3	49.3	23.70	N Line	PASS
0.55	38.2		20.5	10.00	56.0	46.0	25.50	N Line	PASS
1.07	36.9		25.1	10.00	56.0	46.0	20.90	N Line	PASS
2.24	41.9		29.4	10.00	56.0	46.0	16.60	N Line	PASS
4.20	47.4		31.9	10.00	56.0	46.0	14.10	N Line	PASS

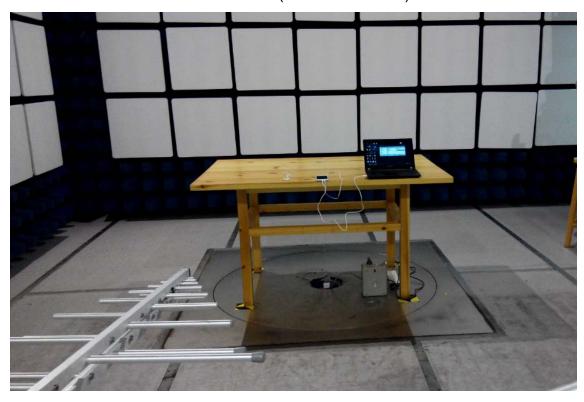


ANNEX B TEST SETUP PHOTOS

B.1 Radiated Field Strength Measurement



30MHz-1GHz (CAMERA MODE)

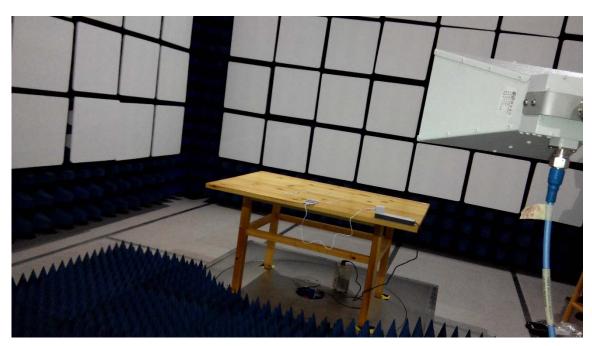


30MHz-1GHz (USB MODE)





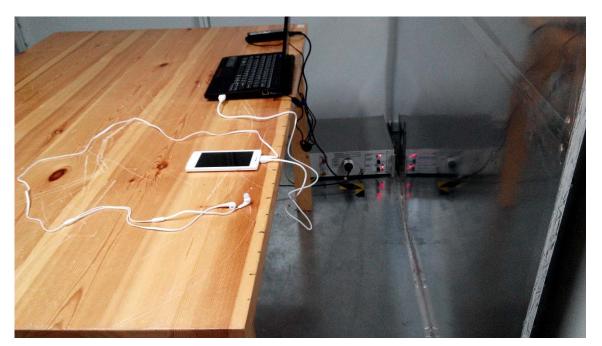
1GHz-6GHz (USB MODE)



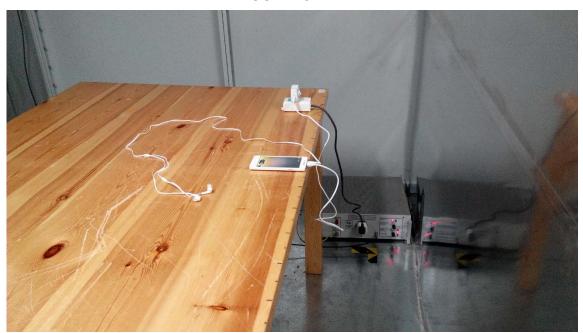
1GHz-6GHz (CAMERA MODE)



B.2 Conducted Emission



USB MODE

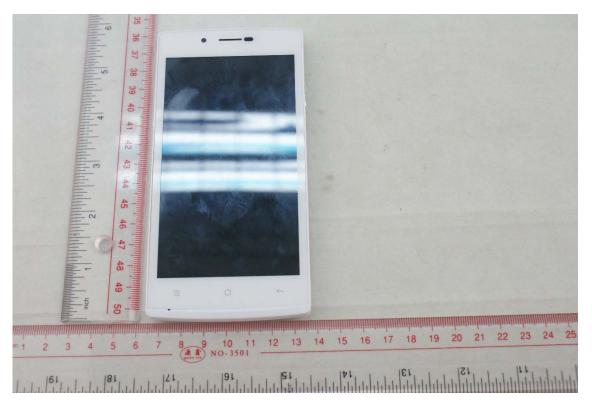


CAMERA MODE



ANNEX C EUT PHOTOS

C.1 Appearance of the EUT

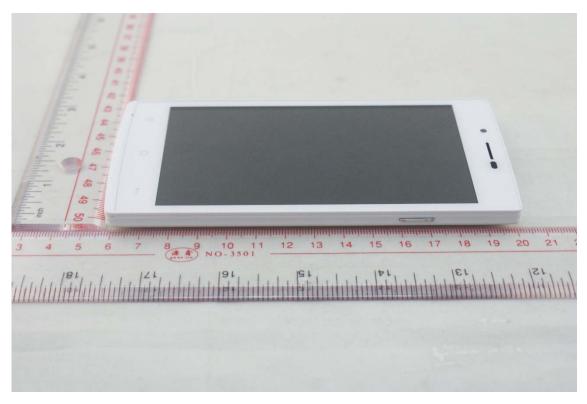


THE FRONT OF EUT



THE BACK OF EUT





THE LEFT OF EUT



THE RIGHT OF EUT





THE UP OF EUT

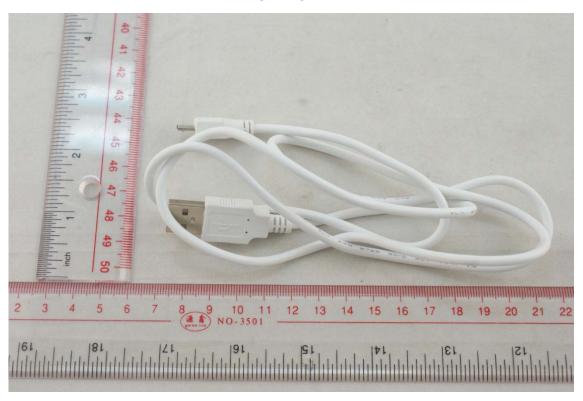


THE DOWN OF EUT





CHARGER



DATA CABLE





EARPHONE



C.2 Inside of the EUT

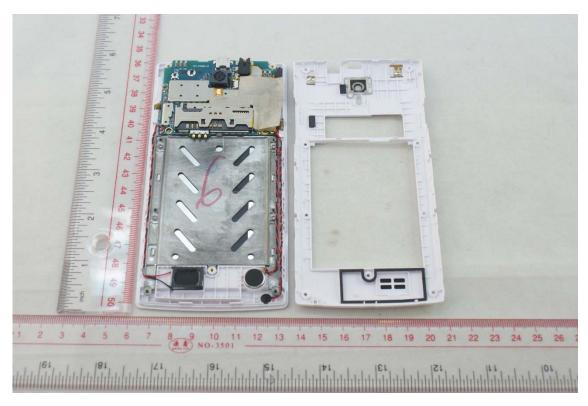


EUT UNCOVER VIEW 1

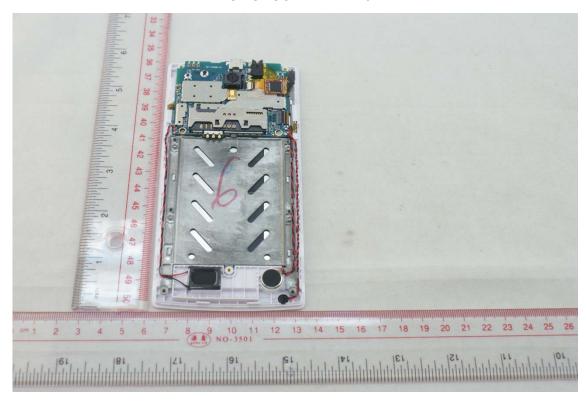


EUT UNCOVER VIEW 2



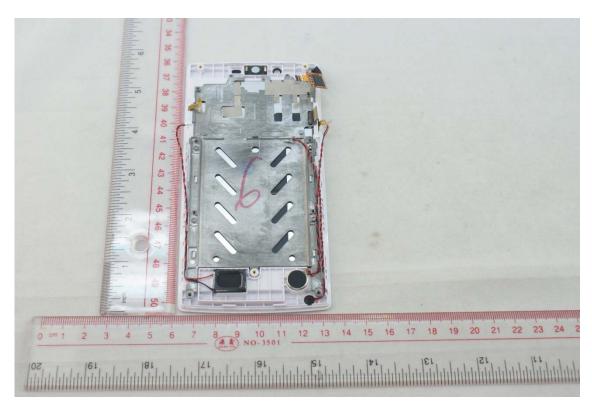


EUT UNCOVER VIEW 3



EUT UNCOVER VIEW 3



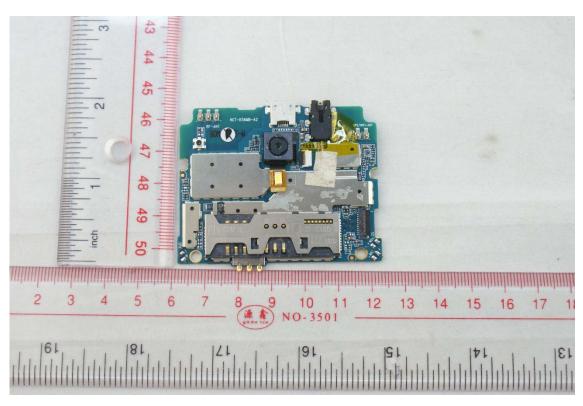


EUT UNCOVER VIEW 4

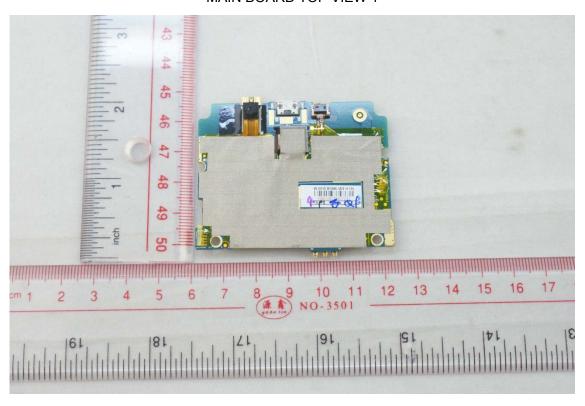


BATTERY



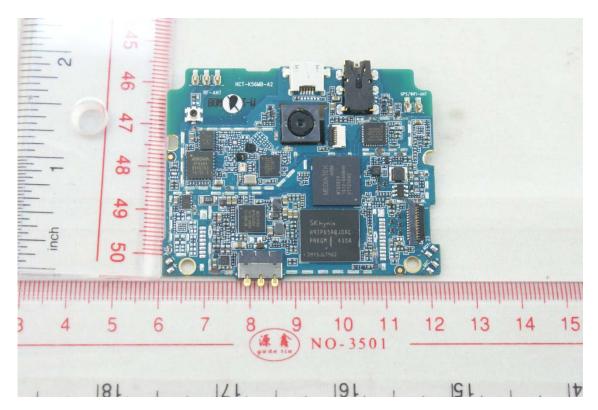


MAIN BOARD TOP VIEW 1

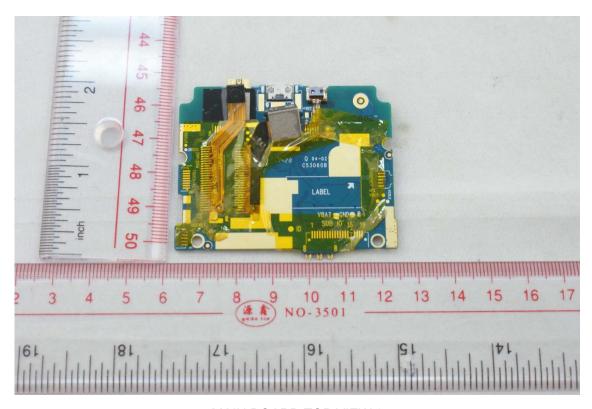


MAIN BOARD BACK VIEW 1



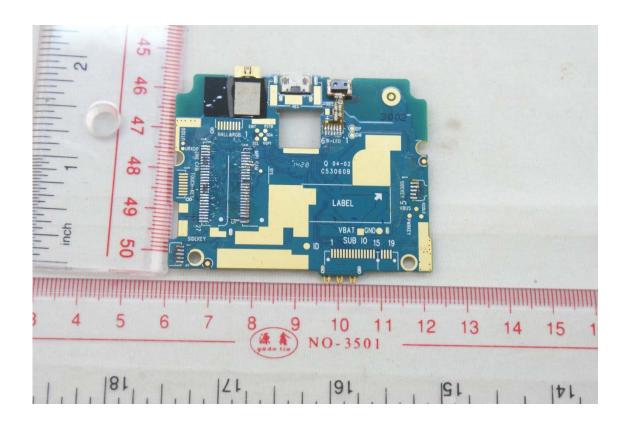


MAIN BOARD TOP VIEW 2

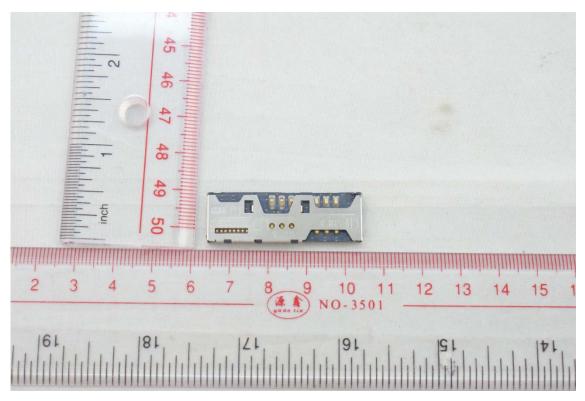


MAIN BOARD TOP VIEW 3



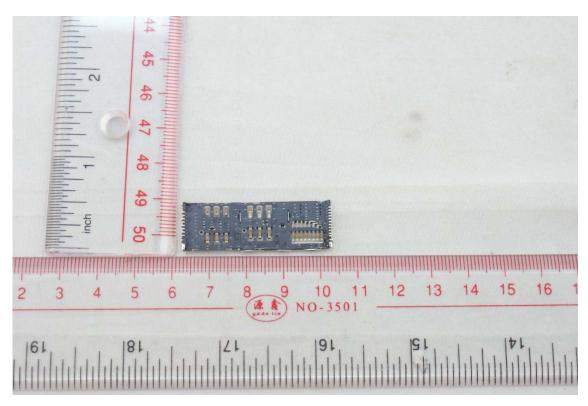


MAIN BOARD TOP VIEW 4



MAIN BOARD TOP VIEW 5





MAIN BOARD TOP VIEW 6

--END OF REPORT--